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Development of Spark Plasma Sintering (SPS) for preparation of nanocrystalline *p*-type Bi_{0.5}Sb_{1.5}Te₃ thermoelectric material

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Bismuth antimony telluride is the most commonly used commercial thermoelectric material for power generation and refrigeration over the temperature range of 200 - 400 K. Improving the performance of these materials is complected balance of optimizing thermoelectric properties. Decreasing the grain size of Bi_{0.5}Sb_{1.5}Te₃ significantly reduces the thermal conductivity due to the scattering phonons on the grain boundaries. In this work, it is shown the advances of spark plasma sintering (SPS) for preparation of nanocrystalline *p*-type thermoelectrics based on Bi_{0.5}Sb_{1.5}Te₃ at different temperatures (240, 350, 400°C). The complex study of structural and thermoelectric properties of Bi_{0.5}Sb_{1.5}Te₃ were presented. The high dimensionless thermoelectric figure of merit *ZT* ~ 1 or some more over 300 - 400 K temperature range for nanocrystalline *p*-type Bi_{0.5}Sb_{1.5}Te₃ was obtained. Key words: Bi_{0.5}Sb_{1.5}Te₃, Spark plasma sintering (SPS), thermoelectric properties, figure of merit *Z*.

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Introduction

Choice criteria of effective thermoelectric material was stated by A.F. Ioffe as "*The material with the electrical conductivity like a good metal and the thermal conductivity like good isolator*". A.F. Ioffe deserves a full credit for understanding that namely "middle" class of materials – semiconductors can provide the best thermoelectric performance as thermoelectric materials [1]. The conversion efficiency of heatenergy to electric power depends on figure of merit of thermoelectric material – factor *Z*, which his expressed as:

$$Z = \frac{S^2 \sigma}{\kappa},\tag{1}$$

where S is Seebeck coefficient, σ is electrical conductivity and κ is thermal conductivity of thermoelectric material.

At acoustic phonon scattering of charge carriers (charge carriers mean free path $l = l_0 E^r$, where l_0 is constant, *E* is charge carrier energy, scattering parameter r = 0), Seebeck coefficient is written as:

$$S = \frac{k_0}{e} \left| 2 \frac{F_1(\mu^*)}{F_0(\mu^*)} - \mu^* \right|,$$
 (2)

where k_0 is Boltzmann constant, e is electron charge, F_i are Fermi integrals, μ^* is reduced Fermi level (for conduction band $\mu^* = (E_c - E_F)/k_0T$, E_c is the bottom of conduction band, E_F is Fermi level, for valence band $\mu^* = (E_F - E_V)/k_0T$, E_v is the top of valence band).

The electrical conductivity σ of a semiconductor with density of charge carriers n(p) is given by wellknown formula:

$$\sigma = en(p)\mu_n(\mu_p), \tag{3}$$

where n(p) is electron (hole) concentration, $\mu_n(\mu_p)$ is mobility of charge carriers.

The hole concentrations in the valence band is:

$$p = 4\pi \frac{\left(2m_p^* k_0 T\right)^{\frac{3}{2}}}{h^3} F_{1/2}\left(\mu^*\right), \tag{4}$$

where m_{p}^{*} is the density of state effective (DOS) mass of holes. The mobility in a semiconductor with a simple parabolic band is written as:

$$\mu = e\tau / m_c^*, \qquad (5)$$

where τ is the average pulse relaxation time (the time defining a mean free path), and m_c^* is effective mass of charge carrier.

Heat transport is determined by total thermal conductivity κ of semiconductor which consists of three components: lattice thermal conductivity κ_L by phonons, electronic thermal conductivity κ_e by free electrons or holes and ambipolar thermal conductivity κ_a by electron - hole pairs in the intrinsic conduction region:

$$\kappa = \kappa_{\rm L} + \kappa_{\rm e} + \kappa_{\rm a}. \tag{6}$$

The heat transport by any elementary excitations (phonons) can be described by formula:

$$\kappa_L = \frac{1}{3} C_v v^3, \qquad (7)$$

where C_v is the specific heat at constant volume, v is the velocity of propagation of an elementary excitation. Electronic thermal conductivity can be described by Wiedemann - Franz law:

$$\kappa_e = L_0 \sigma T \tag{8}$$

where L_0 is constant known as Lorenz number. For scattering by the acoustic phonons, Lorenz number is given by:

$$L_0 = 2 \left(\frac{k_0}{e}\right)^2. \tag{9}$$

Seebeck coefficient S decreases with a growth of charge carriers concentration n(p) and in a metal with charge carriers concentration~ 10^{22} cm⁻³ S close to zero. At the same time, electrical conductivity σ increases with growth of charge carriers concentration n(p). Therefore, dependence of product $S^2\sigma$ as a function of Fermi level $E_{\rm F}$ has the bell-shaped form. The maximum $S^2\sigma$ is achieved, when $E_{\rm F}$ is close to the bottom of conduction band in *n*-type semiconductor or close to the top of valence band for *p*-type semiconductor. In this case value of Seebeck coefficient $S \approx 180 \pm 10 \mu V/K$ and charge carriers concentration $n(p) \sim 5 \times 10^{19} \text{ cm}^{-3}$. When charge carriers concentration $n(p) \sim 5 \times 10^{19} \text{ cm}^{-3}$, then heat transport is determined mainly by lattice thermal conductivity κ_L by phonons. For the optimal charge carrier concentration (reduced Fermi level $\mu^* \approx 0$), figure of merit Z practically depends on three parameters:

$$Z \sim m_n^{*3/2} (\mu / \kappa_L)$$
. (10)

Now we can formulate the choice criteria of the effective thermoelectric material:

1. Semiconductor material (elemental, compound, alloy, composite, multilayer, superlattice, lowdimension) should preferably consists of heavy atoms that will cause a low frequency of thermal vibrations of lattice and, correspondingly, significant decrease in lattice thermal conductivity κ_L .

2. Semiconductor material should have high dielectric constant $\epsilon \ge 100$, that reduces significantly the scattering of charge carriers by impurity ions; and small effective mass of major charge carriers. These two requirements provide high mobility of charge carriers μ . Note, that high dielectric constant ϵ leads to decrease in ionization energy of the impurity atoms (which practically approaching zero). As a result, energy level of impurity merges with the valence band, and concentration of holes in the valence band in *p*-type becomes constant (like a metal) and equals to concentration of dopant from 0 K to the onset of intrinsic conductivity.

3. Semiconductor material should have multivalley structure (equivalent ellipsoids) of the valence band. This leads to an increase in concentration of charge carriers and, correspondingly, the electrical conductivity σ , which is proportional to the number of ellipsoids, without changing energy of Fermi level $E_{\rm F}$.

4. Impurity doping of semiconductor material to the level $p \ge 10^{19}$ cm⁻³ should be possible that will provide optimal Fermi level energy E_F , and, having in mind maximum value of S² σ , will mean $(E_v - E_F) \sim 0$ eV.

5. Band gap of semiconductor over operating temperature range of thermoelectric material should be not less than $E_g \ge 8 k_o T$ to minimize contribution of thermally generated minority charge carriers to total electrical conductivity leading to decrease in thermoelectric efficiency.

6. Creation of binary solid solutions with a goal of increasing the ratio of carrier mobility to lattice conductivity (A.F. Ioffe idea).

7. Good mechanical properties [2-3].

Alloys of Bi₂Te₃ and Sb₂Te₃ are the best performing p-type thermoelectrics near room temperature and have been the subject of extensive engineering efforts [4-10]. The main properties of p-type thermoelectric material on (BiSb)₂Te₃ semiconductor alloys are presented in Table 1. Bi₂Te₃ based compounds have defect structure [11]. Thermodynamic nature of defect systems in chalcogenide materials are decribed such carefully in [12, 13].

In the last years interest in low dimensional thermoelectric structures has increased due to the possibility of sharply increasing their figire of merit Z [14, 15]. The first effect of a significant increase in Z were observed in quantum wells of the thermoelctric materials. However such structures with dimensions in order some μ m can not be used for fabrication of the thermolectric devices in different real applications. Therefore researchers have turned their attention to the creation of bulk and film nanostructured thermoelectrics [16-19].

The spark plasma sintering (SPS) technology was used after the nanopowder fabrication in the high energy ball mill. SPS is a new method of sintering under pressure with the pulse direct current transmission. This metod allows to sinter specimens at relatively low temperatures during a short time. SPS syntering restricticts the undesirable growth of grains due to recrystallization process.

Table 1

The	The properties of <i>p</i> -type thermoelectric material	1 OII (DISU)21C38		5
Composition	Parameter	Symbol	Value	Reference
Bi ₂ Te ₃	Melting point	T _m	858 K	[4]
Bi ₂ Te ₃	Band-gap at 300 K	Eg	0.13 eV	[4]
Bi ₂ Te ₃	Temperature dependence of band-gap	$dE_{\rm g}/dT$	-9x10 ⁻⁵ eV/K	[4]
Bi ₂ Te ₃	Debye temperature	T _D	155.5 K	[4]
Bi ₂ Te ₃	Number of ellipsoids at valence band	$N_{ m v}$	6	[4]
Bi ₂ Te ₃	Density of states effective mass of holes	<i>m</i> * _p	0.69 <i>m</i> _o	[4]
Bi ₂ Te ₃	Hole mobility at $T = 300$ K	$\mu_{ m p}$	510 cm ² /Vs	[4]
Bi ₂ Te ₃	Scattering parameter	r _p	0	[4]
Bi ₂ Te ₃	Dielectric constant	εο	400	[4]
Bi ₂ Te ₃	Intrinsic carrier concentration at $T = 300$ K	ni	10^{18} cm^{-3}	[4]
Bi ₂ Te ₃	Lattice thermal conductivity at $T = 300 \text{ K}$	$\kappa_{ m L}$	1.4 W/mK	[4]
Bi _{0.5} Sb _{1.5} Te ₃	Lattice thermal conductivity at $T = 300$ K	$\kappa_{ m L}$	1.0 W/mK	[5]
Bi ₂ Te ₃	Dimensionless Figure of Merit at $T = 300 \text{ K}$	ZT	0.8	[4]
Bi _{0.5} Sb _{1.5} Te ₃	Dimensionless Figure of Merit at $T = 300 \text{ K}$	ZT	1.1	[5, 6]

The main properties of *p*-type thermoelectric material on (BiSb)₂Te₃semiconductor alloys

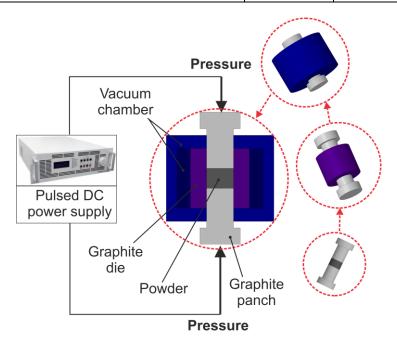


Fig. 1. Schematic view of SPS technique set up.

I. Experimental procedure

Synthesis of materials was carried out in quartz ampoules evacuated to a residual pressure of 10^{-4} mbar. The ampoules were subjected to detailed purification, which included washing in HNO₃:H₂SO₄ mixture and frequent cleaning with distilled water and isopropanol. Polycrystalline samples Bi_{0.5}Sb_{1.5}Te₃ were synthesized by melting the elements Bi (Alfa Aesar, 99.999 %), Te (Alfa Aesar, 99.999 %) and Sb (Alfa Aesar, 99.999 %) at 750 °C in a rocking furnace that can vary the angle in the range of $\pm 30^{\circ}$ with a period of 15 s to force mixing the components. At temperature~ 900 °C the ampoule was taken from the furnace and quenched in cold water. The ingots were subjected to mechanical activation in a protective atmosphere in AGO-2U high energy planetary ball mill.

After that the nanopowder was compacted in a protective atmosphere at room temperature into tablets into a 20-mm diameter and 5-mm thickness under pressure of 1 GPa. Then, these tablets were densified by Spark Plasma Sintering (SPS) method, which was first developed by Prof. Z. Dashevsky for Bi₂Te₃ and PbTe thermoelectrics [19-21]. The schematic view of SPS technique set is presented in Fig. 1. The temperature of sintering was at 400°C during 20 min under an axial

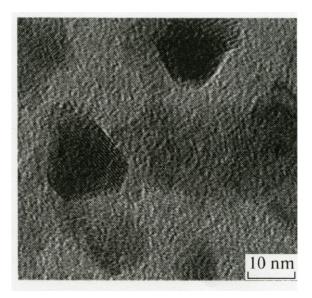


Fig. 2. Electron microscope image of Bi_{0.5}Sb_{1.5}Te₃ powder particles.

compressive stress of 60 MPa in an argon atmosphere. The heating/cooling rate was 50 °C/min.

Phase identification was performed with the Bruker D8 advance X-ray diffractometer using $Cu_{K\alpha 1}$ radiation $(\alpha = 1.5406 \text{ Å}, \Delta 2\Theta = 0.005^{\circ}, 2\Theta \text{ range } 10 - 120^{\circ})$ with Bragg-Brentano geometry. Lattice parameters refinement and other crystallographic calculations were performed with the program package GSAS-II. For SEM and EDX analyses, samples were embedded in conductive resin, and subsequently polished, finally using 1 µm diamond powder in a slurry. The analysis of the samples chemical composition was performed using scanning electron microscopy (JEOL JSM-6460LV Scanning Electron Microscope) equipped with energy dispersive X-ray spectroscopy. The uniformity of the Seebeck coefficient at sample surface (10 mm x 2.2 mm) was performed by the scanning thermoelectric microprobe (STM) technique with 50 µm resolution.

The Seebeck coefficient *S* and electrical conductivity σ were measured by commercial apparatus SBA 458 Nemesis developed by Netzsch. Measurements were spent in argon at the temperature range from 25 to 500 °C. Thermal diffusivity α was measured by the Netzsch LFA 457 equipment and the specific heat capacity C_p was derived from a reference sample (Pyroceram 9606). The samples were firstly spray coated with a thin layer of graphite to minimize errors from the emissivity of the material and from laser beam reflection caused by shiny pallet surface. Thermal conductivity was calculated using the equation:

$$\kappa = \alpha \rho c_p, \tag{11}$$

where ρ is the density obtained by Archimedes principle at the discs from PECS. The uncertainty of the Seebeck coefficient and electrical conductivity measurements is 6%, the uncertainty of the thermal conductivity is estimated to be within 8%. The combined uncertainty for the experimental determination of ZT is ~ 20%.

II. Results and discussion

2.1. The structure of Bi_{0.5}Sb_{1.5}Te₃ powder

It was observed by the transmission electron microscopy powder particles preserved $Bi_{0.5}Sb_{1.5}Te_3$ composition have good structure perfection. The average size of powder particles, determined from high resolution transmission microscopy ~ 10 - 12 nm (Figure 2).

2.2. The structure of Bi_{0.5}Sb_{1.5}Te₃ specimens prepared by SPS method

The specimens, compacted from nanopwders at room temperature, after Spark Plasma Sintering, were mechanically strong at the sintering temperatures. Pores were absent. The cleavage surface images, were inverstigated in the scanning electron microscope, are presented in Fig. 3. The crystallites growth is observed at 350 - 400°C temperature range. In the remaining samples the structure is finely dispersed. Thus, mechanical milling consequences are preserved, and, at temperatures of 350°C and higher, particles grow, pointing to the active recrystallization process.

2.3 Thermoelectric properties

Seebeck coefficient (a) electrical conductivity (b), thermal conductivity (c) and calculated a dimensionless figure of merit ZT (d) have been measured in the temperature range of 200 - 400 K for specimens, preparated by the SPS at different temperatures (240, 350, 400°C).

The lattice thermal conductivity κ_L was determined by subtracting the electronic thermal conductivity κ_e from the total thermal conductivity κ (Figure 4(c)). The values of κ_e were calculated using Wiedemann-Franz law (Eq. 8). The Lorentz number *L*, which was calculated using the following equation [5]:

$$L = \left(\frac{k_0}{e}\right)^2 \left[3\frac{F_2(\mu^*)}{F_0(\mu^*)} - \left(2\frac{F_2(\mu^*)}{F_0(\mu^*)}\right)^2\right],$$
 (12)

where k_0 is Boltzmann constant, *e* is the electron charge, $\mu^* = E_{F}/k_0T$ is the reduced Fermi energy, and $F_x(\mu^*)$ is the Fermi integral given by:

$$F_{x}(\mu^{*}) = \int_{0}^{\infty} \frac{E^{x} dE}{1 + \exp(E - \mu^{*})} .$$
(13)

At acoustic phonon scattering of electrons, the reduced Fermi energy μ^* can be obtained from fitting the Seebeck coefficient [5]:

$$S = \frac{k_0}{e} \left[\frac{2F_1(\mu^*)}{F_0(\mu^*)} - \mu^* \right].$$
 (14)

Values of the lattice thermal conductivity κ_L at 300 K for specimens preparated by SPS at 350 - 400°C ≈ 0.8 W/m K. This value of κ_L for specimens with nanocrystlline structure on ~ 30 % less than κ_L for best Bi_{0.5}Sb_{1.5}Ten_xTe₃ polycrystals prepared by hot extrusion [5]. A significant decrease in the value of κ_I may be due to the scattering of long wave phonons on the grain boundaries [22, 23].

It is shown the high value of ZT on a level ≈ 1 and some more over 300 - 400 K temperature range for nanocrystalline Bi_{0.5}Sb_{1.5}Ten_xTe₃ specimens preparated

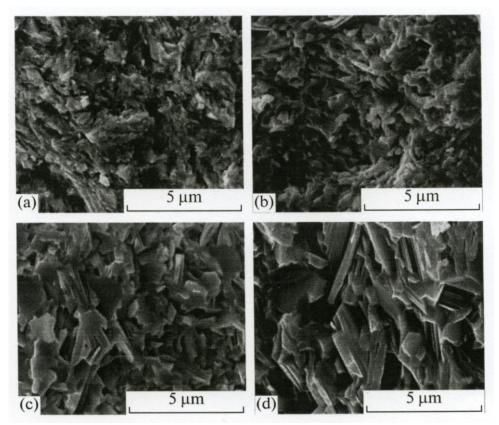


Fig. 3. Secondary emission images of specimens, preparated by the SPS at temperatures of (a) 240, (b) 300, (c) 350, and (d) 400°C.

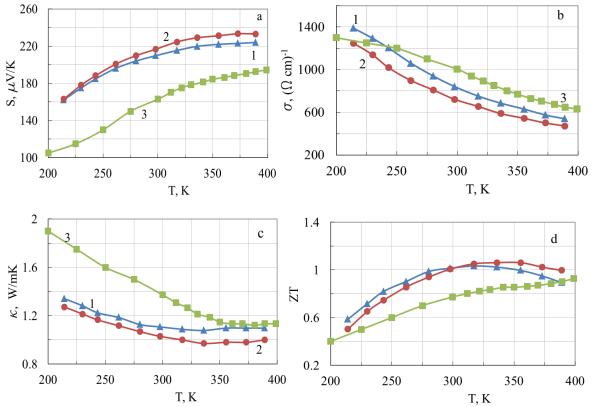


Fig. 4. Seebeck coefficient (a), electrical conductivity (b), thermal conductivity (c) and dimensionless figure of merit ZT (d) as a function of temperature for Bi_{0.5}Sb_{1.5}Ten_xTe₃ specimens preparated by SPS at different temperatures. 1 - 400, 2 - 350, 3 - 240°C respectively.

by SPS at 350 - 400°C temperatures (Fig. 4d).

Conclusions

Spark plasma sintering (SPS) under pressure with the pulse direct current transmission was used for preparation of nanocrystalline p-type Bi_{0.5}Sb_{1.5}Te₃ thermoelectric material.

Based on structure studies, at the syntering temperatures of 350 °C and higher recrystallization process was observed. It is resulting in increasing of the grain size of the thermoelectric material.

The thermoelectric properties, such as the electrical and thermal conductivities, Seebeck coefficient, for specimens $Bi_{0.5}Sb_{1.5}Te_3$, preparated by the SPS at different temperatures (240, 350, 400 °C) has been

investigated over 200 - 400 K temperature range. The high value of $ZT \approx 1.1$ over 300 - 400 K temperature range for nanocrystalline *p*-type Bi_{0.5}Sb_{1.5}Te₃ specimens was obtained. It should be noted, that for specimens preparated by SPS at 350 - 400°C the significant decrease in the value of κ_L is observed, which may be explained by scattering of long wave phonons on the grain boundaries.

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Розвиток іскрового плазмового спікання (ІПС) для отримання нанокристалічного термоелектричного матеріалу Ві_{0.5}Sb_{1.5}Te₃ р-типу

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Телурид сурми вісмуту є найбільш часто використовуваним комерційним термоелектричним матеріалом для виробництва електроенергії та охолодження в діапазоні температур 200 - 400 К. Поліпшення експлуатаційних характеристик цих матеріалів доповнюється балансом оптимізації термоелектричних властивостей. Зменшення розміру зерен $Bi_{0.5}Sb_{1.5}Te_3$ суттєво знижує теплопровідність за рахунок розсіювання фононів на границях зерен. У цій роботі показано досягнення іскрового плазмового спікання (IПС) для отримання нанокристалічних термоелектриків р-типу на основі $Bi_{0.5}Sb_{1.5}Te_3$ при різних температурах (240, 350, 400°С). Було представлено комплексне дослідження структурних та термоелектричних властивостей $Bi_{0.5}Sb_{1.5}Te_3$. Отримано високе значення безрозмірної термоелектричної добротності $ZT \sim 1$ і навіть трохи більше в діапазоні температур 300 - 400 К для нанокристалічного $Bi_{0.5}Sb_{1.5}Te_3$ р-типу провідності.

Ключові слова: Ві0,5Sb1,5Te3, іскрове плазмове спікання (SPS), термоелектричні властивості.